

	Search Terms
1	DISPLACEMENT
2	DISPLACEMENTS
3	DISTRIBUTION
4	DISTRIBUTIONS
5	ELECTRIC
6	ELECTRICS
7	ELECTROMAGNETIC
8	MAGNETIC
9	MAGNETICS
10	PROBE
11	PROBES
12	SAMPLED
13	SAMPLEDS
14	SAMPLER
15	SAMPLERS
16	SAMPLING
17	SAMPLINGS
18	SHIFT
19	SHIFTING
20	SHIFTINGS
21	SHIFTS
22	SPECTRUM
23	SPECTRUMS
24	SHIFTED
25	((SPECTRUM SAME SHIFT) AND ((SAMPLER OR SAMPLED OR SAMPLING) SAME PROBE)) AND ((DISTRIBUTION SAME (SHIFTED OR SHIFTING OR DISPLACEMENT OR SHIFT)) SAME (ELECTROMAGNETIC OR ELECTRIC OR MAGNETIC)))

	T tal	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	568959							
2	48219							
3	856177							
4	54979							
5	3181797							
6	3699							
7	170							
8	1152972							
9	10688							
10	255258							
11	108114							
12	143047							
13	1							
14	20943							
15	3558							
16	238198							
17	4269							
18	569287							
19	283865							
20	614							
21	172030							
22	310891							
23	5747							
24	358284							
25	6	1	5	0	0	0	0	

	U	1	D	document ID	Issue Date	Pages	Title	Current OR
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20030109997 A1	20030612	14		Field distribution measuring method and device	702/76
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030067312 A1	20030410			Voltage testing and measurement	324/753
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030057972 A1	20030327	60		Voltage testing and measurement	324/752
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030012733 A9	20030116			Method of using reduced dimensionality nuclear magnetic resonance spectroscopy for rapid chemical shift assignment and secondary structure determination of proteins	424/9.3
5	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20020041850 A1	20020411			Method of using reduced dimensionality nuclear magnetic resonance spectroscopy for rapid chemical shift assignment and secondary structure determination of proteins	424/9.3
6	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 6512385 B1	20030128			Method for testing a device under test including the interference of two beams	324/753

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Kitayoshi, Hitoshi	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030109997	<input type="checkbox"/>
2			Pfaff, Paul et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
3			Pfaff, Paul et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030057972	<input type="checkbox"/>
4			Szyperski, Thomas A.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
5			Szyperski, Thomas A.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
6	324/752; 324/765		Pfaff, Paul et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>

	Search Terms
1	KITAYOSHI-HITOSHI
2	PROBE
3	PROBES
4	SHIFT
5	SHIFTING
6	SHIFTINGS
7	SHIFTS
8	SHIFTED
9	((KITAYOSHI-HITOSHI.IN.) AND PROBE) AND (SHIFTED OR SHIFTING OR SHIFT)

	T tal	USPAT	US-PGPUB	EPO	JPO	Derwent	IBM TDB	USOCR
1	105							
2	255258							
3	108114							
4	569287							
5	283865							
6	614							
7	172030							
8	358284							
9	4	2	1	1	0	0	0	

	U	1	D	current ID	Issue Date	Pages	Title	Current OR
1	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 20030109997 A1	20030612	14		Field distribution measuring method and device	702/76
2	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5974178 A	19991026	19		Wavesource image visualization method using a partial division fast fourier transform	382/210
3	<input checked="" type="checkbox"/>	<input type="checkbox"/>	US 5656932 A	19970812			Non-contact type wave signal observation apparatus	324/615
4	<input checked="" type="checkbox"/>	<input type="checkbox"/>	EP 1191340 A1	20020327			FIELD DISTRIBUTION MEASURING METHOD AND DEVICE	

	Current XRef	Retrieval Classif	Invent r	S	C	P	2	3	4	5	Image D c. Displayed	PT
1			Kitayoshi, Hitoshi	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 20030109997	<input type="checkbox"/>
2	342/362; 359/9; 382/280		Kitayoshi, Hitoshi	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5974178	<input type="checkbox"/>
3	324/630; 324/76.12		Kitayoshi, Hitoshi	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>
4			KITAYOSHI, HITOSHI	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>		<input type="checkbox"/>